

# Philips Components—Signetics

Document No.	853-0612
ECN No.	99800
Date of Issue	June 14, 1990
Status	Product Specification
ECL Products	

# 100122

## 9-Bit Buffer

### FEATURES

- Typical propagation delay: 0.75ns
- Typical supply current ( $-I_{EE}$ ): 78mA

### DESCRIPTION

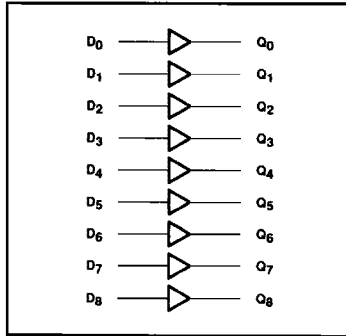
The 100122 contains 9 Buffer Gates, each with a single input and a single output.

All unused inputs can be left open due to integrated pull-down resistors.

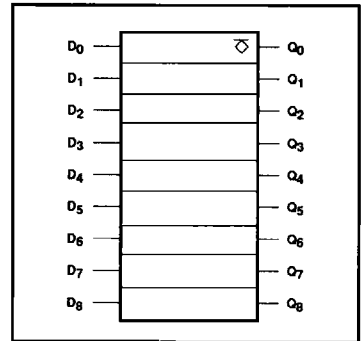
### PIN DESCRIPTION

PINS	DESCRIPTION
$D_0 - D_8$	Data Inputs
$Q_0 - Q_8$	Data Outputs

### LOGIC DIAGRAM



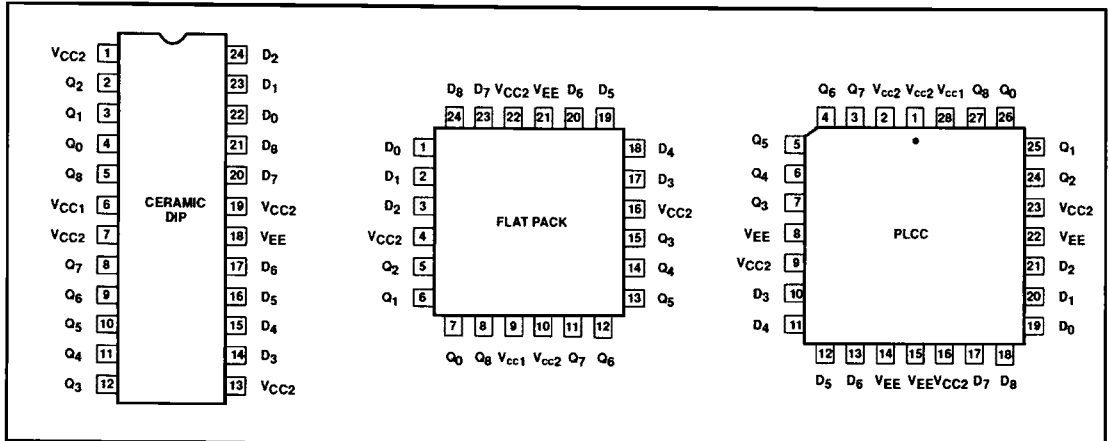
### IEC/IEEE SYMBOL



### ORDERING INFORMATION

DESCRIPTION	ORDER CODE
24-Pin Ceramic DIP (400 mils wide)	100122F
24-Pin Ceramic Flat Pack	100122Y
28-Pin PLCC	100122A

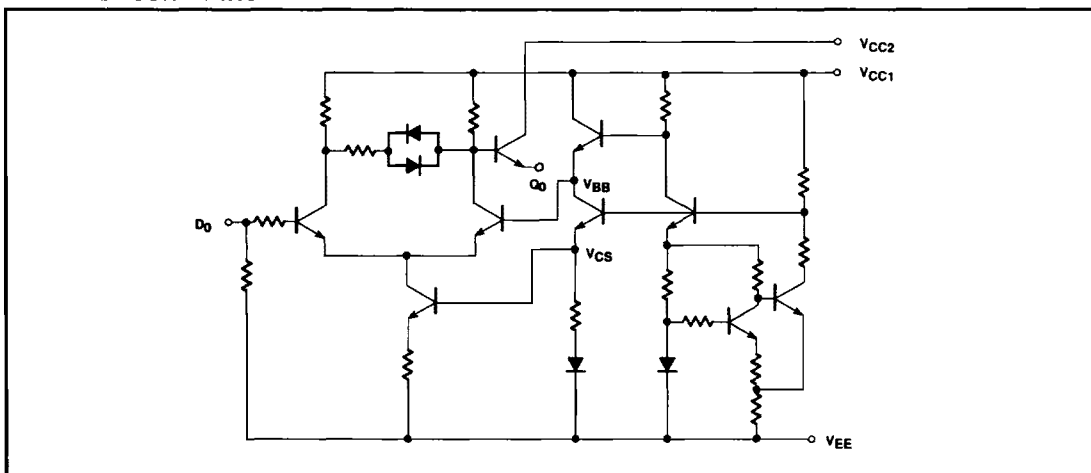
### PIN CONFIGURATIONS



# Buffer

100122

## SIMPLIFIED SCHEMATIC



**ABSOLUTE MAXIMUM RATINGS**  $V_{CC1} = V_{CC2} = \text{ground}$ ,  $T_A = 0^\circ\text{C}$  to  $+85^\circ\text{C}$  unless otherwise specified.

SYMBOL	PARAMETER	LIMITS	UNIT
$V_{EE}$	Supply voltage range	-7.0 to +0.5	V
$V_{IN}$	Input voltage ( $V_{IN}$ should never be more negative than $V_{EE}$ )	$V_{EE}$ to +0.5	V
$I_O$	Output source current (continuous)	-55	mA
$T_S$	Storage temperature range	-65 to +150	$^\circ\text{C}$
$T_J$	Maximum junction temperature	+150	$^\circ\text{C}$

**NOTE:**

Operation beyond the limits set forth in this table may impair the useful life of the device.

## DC OPERATING CONDITIONS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS			UNIT
			MIN.	NOM.	MAX.	
$V_{CC1}, V_{CC2}$	Circuit ground		0	0	0	V
$V_{EE}$	Supply voltage		-4.8	-4.5	-4.2	V
$V_{EE}$	Supply voltage when operating with the 10K or the 10KH ECL family		-5.7			V
$V_{IH}$	High level input voltage	$V_{EE} = -4.2\text{V}$	-1150		-880	mV
		$V_{EE} = -4.5\text{V}$	-1165			
		$V_{EE} = -4.8\text{V}$	-1165			
$V_{IL}$	Low level input voltage	$V_{EE} = -4.2\text{V}$	-1810		-1475	mV
		$V_{EE} = -4.5\text{V}$			-1475	mV
		$V_{EE} = -4.8\text{V}$			-1490	mV
$T_A$	Operating ambient temperature range		0	+25	+85	$^\circ\text{C}$

**NOTE:**

When operating at other than the specified  $V_{EE}$  voltages (-4.2V, -4.5V, -4.8V), the DC and AC electrical characteristics will vary slightly from their specified values.

## Buffer

100122

**DC ELECTRICAL CHARACTERISTICS**  $V_{CC1} = V_{CC2} = \text{ground}$ ,  $V_{EE} = -4.8\text{V}$  to  $-4.2\text{V}$ ,  $T_A = 0^\circ\text{C}$  to  $+85^\circ\text{C}$  unless otherwise specified<sup>1,3,4</sup>

SYMBOL	PARAMETER	TEST CONDITIONS <sup>2</sup>			LIMITS			UNIT
					MIN.	TYP.	MAX.	
$V_{OH}$	High level output voltage		Inputs at $V_{IHMAX}$ or $V_{ILMIN}$ .	$V_{EE} = -4.2\text{V}$	-1020		-870	mV
				$V_{EE} = -4.5\text{V}$	-1025	-955	-880	mV
				$V_{EE} = -4.8\text{V}$	-1035		-880	mV
$V_{OHT}$	High level output threshold voltage	Outputs loaded	Apply $V_{IHMIN}$ or $V_{ILMAX}$ to one input at a time, other inputs at $V_{IHMAX}$ or $V_{ILMIN}$ .	$V_{EE} = -4.2\text{V}$	-1030			mV
				$V_{EE} = -4.5\text{V}$	-1035			mV
				$V_{EE} = -4.8\text{V}$	-1045			mV
$V_{OLT}$	Low level output threshold voltage	with $50\Omega$ to $-2.0\text{V}$ $\pm 0.010\text{V}$	Apply $V_{IHMIN}$ or $V_{ILMAX}$ to one input at a time, other inputs at $V_{IHMAX}$ or $V_{ILMIN}$ .	$V_{EE} = -4.2\text{V}$			-1595	mV
				$V_{EE} = -4.5\text{V}$			-1610	mV
				$V_{EE} = -4.8\text{V}$			-1610	mV
$V_{OL}$	Low level output voltage		Inputs at $V_{IHMAX}$ or $V_{ILMIN}$ .	$V_{EE} = -4.2\text{V}$	-1810		-1605	mV
				$V_{EE} = -4.5\text{V}$	-1810	-1705	-1620	mV
				$V_{EE} = -4.8\text{V}$	-1830		-1620	mV
$I_{IH}$	High level input current	One input under test at $V_{IHMAX}$ , other inputs at $V_{ILMIN}$ .					350	$\mu\text{A}$
$I_{IL}$	Low level input current	One input under test at $V_{ILMIN}$ , other inputs at $V_{IHMAX}$ .			0.5			$\mu\text{A}$
$-I_{EE}$	$V_{EE}$ supply current	All inputs at $V_{IHMAX}$ .			46	78	96	mA

**NOTES:**

- The specified limits represent the worst case values for the parameter. Since these worst case values normally occur at the supply voltage and temperature extremes, additional noise immunity can be achieved by decreasing the allowable operating condition ranges.
- Conditions for testing shown in the tables are not necessarily worst case. For worst case testing guidelines, refer to DC Testing, Chapter 1, Section 3.
- The specified limits shown in the DC electrical characteristics table can be met only after thermal equilibrium has been established. Thermal equilibrium is established by applying power for at least 2 minutes, while maintaining transverse airflow of 2.5 meters/sec (500 linear feet/min) over the device, mounted either in a test socket or on a printed circuit board. Test voltage values are given in the DC operating conditions table.
- The device can function down to  $V_{EE} = -5.7\text{V}$ , allowing operation with either the 10K or the 10KH family. Correction factors can be used to calculate new DC limits for the extended  $V_{EE}$  range. For more information, see Chapters 5 and 10, Section 4.

**AC ELECTRICAL CHARACTERISTICS**Ceramic DIP  $V_{CC1} = V_{CC2} = \text{ground}$ ,  $V_{EE} = -4.8\text{V}$  to  $-4.2\text{V}$ 

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
$t_{PLH}$ $t_{PHL}$	Propagation delay $D_n$ to $Q_n$	Waveform 1	0.45	1.60	0.45	1.45	0.45	1.60	ns
			0.45	1.60	0.45	1.45	0.45	1.60	ns
$t_{TLH}$ $t_{THL}$	Transition time $Q_n$		0.45	1.40	0.45	1.30	0.45	1.30	ns
			0.45	1.40	0.45	1.30	0.45	1.30	ns

**NOTE:**

For AC test setup information, see AC Testing, Chapter 2, Section 3.

## Buffer

100122

## AC ELECTRICAL CHARACTERISTICS

Ceramic DIP  $V_{CC1} = V_{CC2} = \text{ground}$ ,  $V_{EE} = -5.2V \pm 5\%$ 

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
$t_{PLH}$ $t_{PHL}$	Propagation delay $D_n$ to $Q_n$	Waveform 1	0.45	1.60	0.45	1.45	0.45	1.60	ns
			0.45	1.60	0.45	1.45	0.45	1.60	ns
$t_{TLH}$ $t_{THL}$	Transition time $Q_n$		0.45	1.40	0.45	1.30	0.45	1.30	ns
			0.45	1.40	0.45	1.30	0.45	1.30	ns

## NOTE:

For AC test setup information, see AC Testing, Chapter 2, Section 3.

## AC ELECTRICAL CHARACTERISTICS

Flat Pack and PLCC  $V_{CC1} = V_{CC2} = \text{ground}$ ,  $V_{EE} = -4.8V$  to  $-4.2V$ 

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
$t_{PLH}$ $t_{PHL}$	Propagation delay $D_n$ to $Q_n$	Waveform 1	0.45	1.40	0.45	1.25	0.45	1.40	ns
			0.45	1.40	0.45	1.25	0.45	1.40	ns
$t_{TLH}$ $t_{THL}$	Transition time $Q_n$		0.45	1.40	0.45	1.30	0.45	1.30	ns
			0.45	1.40	0.45	1.30	0.45	1.30	ns

## NOTE:

For AC test setup information, see AC Testing, Chapter 2, Section 3.

## AC ELECTRICAL CHARACTERISTICS

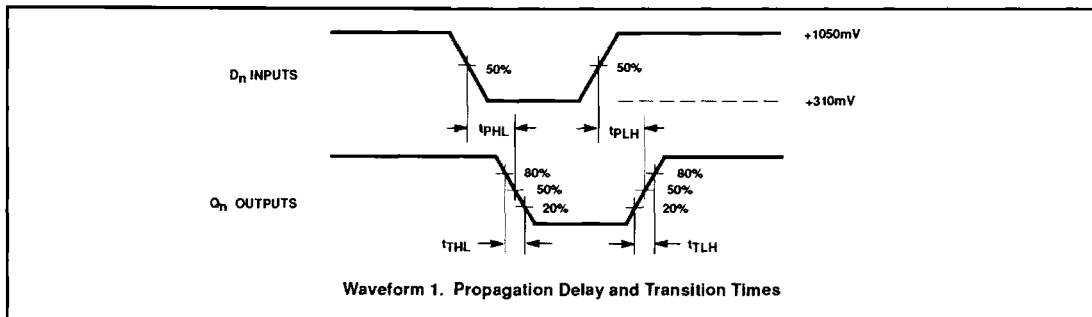
Flat Pack and PLCC  $V_{CC1} = V_{CC2} = \text{ground}$ ,  $V_{EE} = -5.2V \pm 5\%$ 

SYMBOL	PARAMETER	TEST CONDITION	LIMITS						UNIT
			$T_A = 0^\circ\text{C}$		$T_A = +25^\circ\text{C}$		$T_A = +85^\circ\text{C}$		
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
$t_{PLH}$ $t_{PHL}$	Propagation delay $D_n$ to $Q_n$	Waveform 1	0.45	1.40	0.45	1.25	0.45	1.40	ns
			0.45	1.40	0.45	1.25	0.45	1.40	ns
$t_{TLH}$ $t_{THL}$	Transition time $Q_n$		0.45	1.40	0.45	1.30	0.45	1.30	ns
			0.45	1.40	0.45	1.30	0.45	1.30	ns

## NOTE:

For AC test setup information, see AC Testing, Chapter 2, Section 3.

## AC WAVEFORMS



## NOTE:

All power and signal voltages shifted up 2.0V for AC bench test purposes.